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U.S. PATENT DOCUMENTS										10
* EXAMINER INITIAL		DO	CUMENT	DATE	NAME		CLASS	SUBCLASS		ropriate)
HAV	AA	5,8	74,780	02/23/99	Murakami		257	778		
1881	AB	5,7	14,252	02/03/98	Hogerton et al		29	832		200
39V	AC	4,9	29,999	05/29/90	Hoeberechts et al		257	782		
MV	AD	6,0	37,044	03/2000	Giri et al		36/	795		
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BV	AL	JP9	-33608	02/07/97	Japan					
BV	AM	4-3	45041	12/01/92	Japanese Laid-Open Patent					
BV	AN	<u> </u>	75280	07/13/93	Japanese Laid	-Open Patent				
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BV	AP	060	9918	08/10/94	EPO					
0		_		OTHER DOCU	MENTS (Including Au	ıthor, Title, Date, Pertinen	t Pages, etc.)			
A	AR	Denshi Zairyo, April 1996, Kogyo Chosakai, pp. 14-19.								
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